

# TCXO

## PT195 Series

### Sinewave

### 4PAD SMD PACKAGE

#### \* PART NUMBERING GUIDE

PT195 - 5 S 10 3D - 10.000M

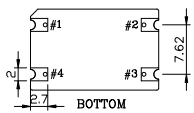
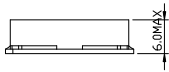
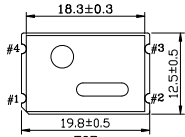
Supply Voltage  
5 : 5.0V  
3 : 3.3V  
Output  
S : Sinewave

Frequency  
M : MHz

Stability vs. Temperature  
See Table1

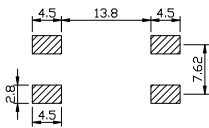
Temperature Range  
Table2

#### MECHANICAL DIMENSIONS

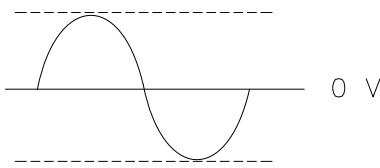


**PIN CONNECTION**  
# 1 V.C or N.C  
# 2 GND  
# 3 OUTPUT  
# 4 Vcc

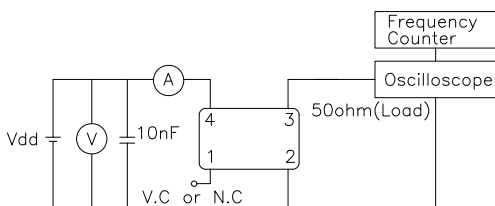
#### Recommended Soldering Pattern



#### OUTPUT WAVEFORM



#### TEST CIRCUIT



#### ELECTRICAL SPECIFICATION

Frequency range	1.000MHz to 600.000MHz (All combinations for Frequency in the range and temp. stability can't be available, please contact factory.)
Frequency Stability vs. Temperature vs. Supply Voltage vs. Load vs. Aging	±0.5 ppm to ±5.0ppm ±0.1 / ±0.2 ppm max / Vdd ± 5% ±0.2 ppm max /15pF ±10% ±1.0 ppm max/ year
Temperature Range Operating Storage	See Table 2 -55°C to 125°C
Supply Voltage	3.3V ± 5% 5.0V ± 5%
Input Current Sinewave	1.00MHz ~ 600.000MHz 10.0mA max ~ 50mA max
Output characteristics	Sinewave Level 3.3V 0 dBm typ 5.0V +5 dBm typ Load 50Ω
Phase Noise (typical) @100MHz	-80 dBc / Hz @ 10Hz -120 dBc / Hz @ 100Hz -140 dBc / Hz @ 1KHz -150 dBc / Hz @ 10KHz -160 dBc / Hz @100KHz
Frequency Adjustment	±3ppm min by internal trimmer

#### ENVIRONMENTAL & MECHANICAL SPECIFICATION

Shock	MIL-STD-883C, Method 2002, Condition B
Vibration	MIL-STD-883C, Method 2007, Condition A
Solderability	MIL-STD-883C, Method 2003
Seal integrity	MIL-STD-883C, Method 1014, Condition C & A2
Marking	MIL-STD-202F, Method 215

#### TABLE1

Symbol	Stability
05	±0.5ppm
10	±1.0ppm
15	±1.5ppm
20	±2.0ppm
25	±2.5ppm
30	±3.0ppm
35	±3.5ppm
50	±5.0ppm

#### TABLE2

Symbol	Temp.	Symbol	Temp.
0	0°C	A	50°C
1	-10°C	B	60°C
2	-20°C	C	70°C
3	-30°C	D	75°C
4	-40°C	E	80°C
		F	85°C